

PROGRESS BY PHYSICS

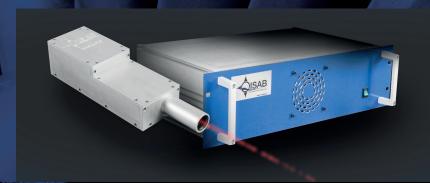


CWS 640

A robust laser system for process inline measurment of surface quality parameters in the nanometer range.

CWS 640 consists of

- · CWS optical head
- CWS power unit with uninterrupted power supply
- CWS software for analyze and visualization





MARKET SEGMENTS

Wherever objective measurment and control of surface quality are required in your business.













SURFACE QUALITY DETECTION

FOR EVERY PROCESS



APPLICATIONS & BENEFITS

WITH AUTOMATED INLINE METROLOGY INSPECTION

CWS APPLICATIONS AND SIGNIFICANCES

- Suitable for automated inline processes
- Robust system, therefore suitable for automated inline metrology inspection
- Fast inline surface measurements of:
 - Roughness
 - Surface errors
 - Assymetry and assymetry angle
 - Structure and structure angle
 - Gloss
- Easy to determine and follow up surface quality
- Non-contact measurement
- Areal surface measurment
- Independent on surface texture orientation
- Replaces manual inspections

CWS BENEFITS AND ADDED VALUES

- Objective measurements
- · Shorter process time
- Possibility for process optimizations
- Automating of previous manual process
- Inline surface process control
- Less scrap by faster inline surface quality inspection
- Enhanced tool maintenance and replacement scheduling

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